

March 2013

FDP12N50 / FDPF12N50T N-Channel UniFETTM MOSFET 500 V, 11.5 A, 650 m Ω

Features

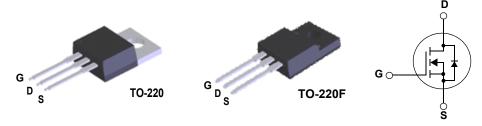
- $R_{DS(on)}$ = 550 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 6 A
- Low Gate Charge (Typ. 22 nC)
- Low Crss (Typ. 11 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

Applications

- LCD/LED/PDP TV
- · Lighting
- · Uninterruptible Power Supply

Description

UniFETTM MOSFET is Fairchild Semiconductor[®]'s high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

	J					
Symbol		Parameter		FDP12N50	FDPF12N50T	Unit
V _{DSS}	Drain to Source Voltage	Drain to Source Voltage		5	V	
V _{GSS}	Gate to Source Voltage			±	:30	V
1	Drain Current	- Continuous (T _C = 25°C)		11.5	11.5 *	۸
ID	Diamourient	- Continuous (T _C = 100°C)		6.9	6.9 *	Α
I _{DM}	Drain Current	- Pulsed	(Note 1)	46	46 *	Α
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	2) 456		mJ
I _{AR}	Avalanche Current		(Note 1)	1	1.5	Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)) 16.7		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	4	4.5	V/ns
D	Dower Dissinction	$(T_C = 25^{\circ}C)$		165	42	W
P_{D}	Power Dissipation	- Derate above 25°C		1.33	0.3	W/°C
T _J , T _{STG}	Operating and Storage Tempera	ture Range		-55 to	o +150	٥С
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	οС	

^{*}Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDP12N50	FDPF12N50T	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.75	3.0	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ. 0.5		-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	62.5	

Package Marking and Ordering Information T_C = 25°C unless otherwise noted

D	evice Marking	Device	Package	Reel Size	Tape Width	Quantity
	FDP12N50	FDP12N50	TO-220		-	50
	FDPF12N50T	FDPF12N50T	TO-220F	-	-	50

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$	500	-	-	V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.5	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 500V, V _{GS} = 0V	-	-	1	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 400V, T_C = 125^{\circ}C$	-	-	10	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 6A$	-	0.55	0.65	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40V, I_{D} = 6A$	ı	11.5	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05V V 0V		-	985	1315	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		-	140	190	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112		-	11	17	pF
Q_{g}	Total Gate Charge at 10V			-	22	30	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 11.5A$		-	6	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V	(Note 4)	-	9	-	nC

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time		-	24	60	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_D = 11.5A$	-	50	110	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25\Omega$	-	45	100	ns
t _f	Turn-Off Fall Time	(Note 4)	-	30	70	ns

Drain-Source Diode Characteristics

I_S	Maximum Continuous Drain to Source Dio	Maximum Continuous Drain to Source Diode Forward Current		-	11.5	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	46	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 11.5A	-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 11.5A	-	375	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	3.5	-	μС

Notes:

^{1.} Repetitive Rating: Pulse width limited by maximum junction temperature

^{2.} L = 6.9mH, I $_{AS}$ = 11.5A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C

^{3.} $I_{SD} \le$ 11.5A, di/dt \le 200A/ μ s, $V_{DD} \le$ BV $_{DSS}$, Starting T $_J$ = 25°C

^{4.} Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

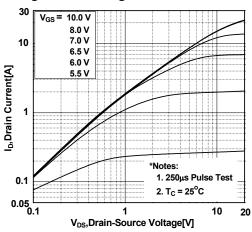


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

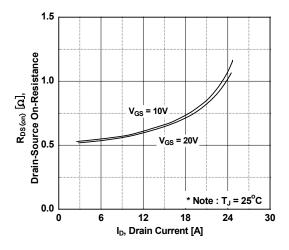


Figure 5. Capacitance Characteristics

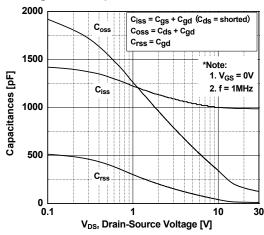


Figure 2. Transfer Characteristics

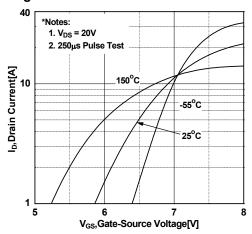


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

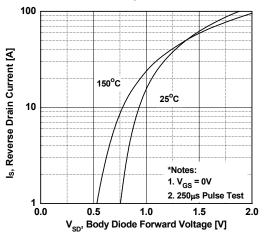
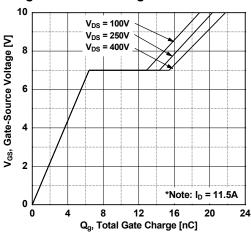


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

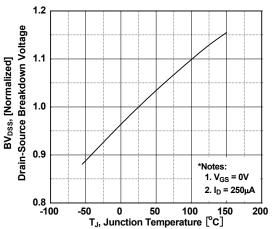


Figure 9-1. Maximum Safe Operating Area

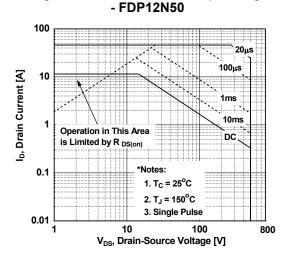


Figure 8. On-Resistance Variation vs. Temperature

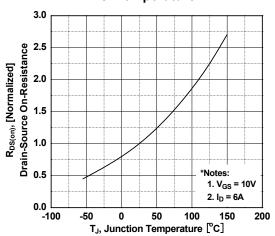


Figure 9-2. Maximum Safe Operating Area - FDPF12N50T

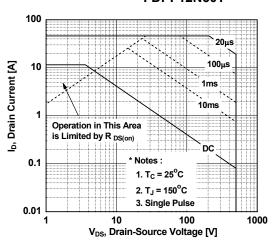
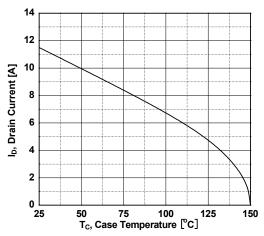


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve - FDP12N50

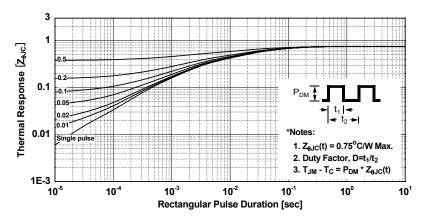
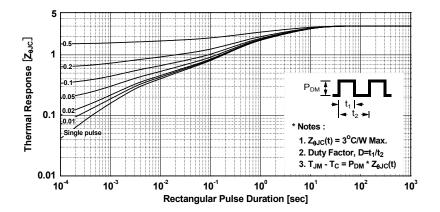
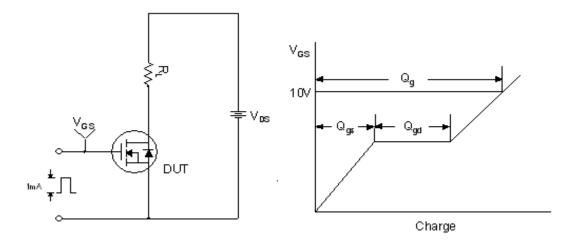


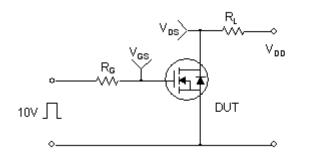
Figure 11-2. Transient Thermal Response Curve - FDPF12N50T

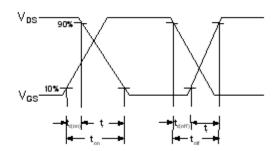


Gate Charge Test Circuit & Waveform

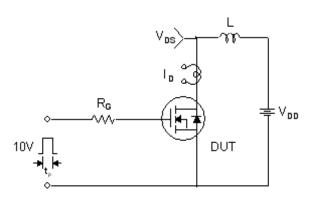


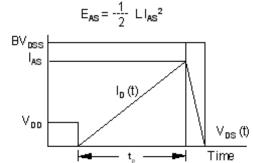
Resistive Switching Test Circuit & Waveforms



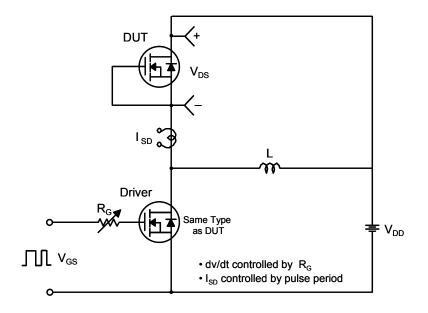


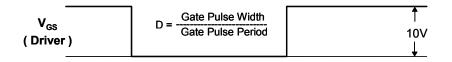
Unclamped Inductive Switching Test Circuit & Waveforms

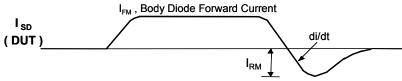




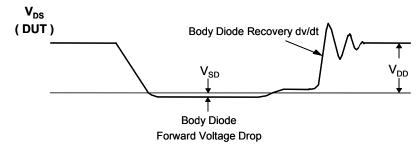
Peak Diode Recovery dv/dt Test Circuit & Waveforms





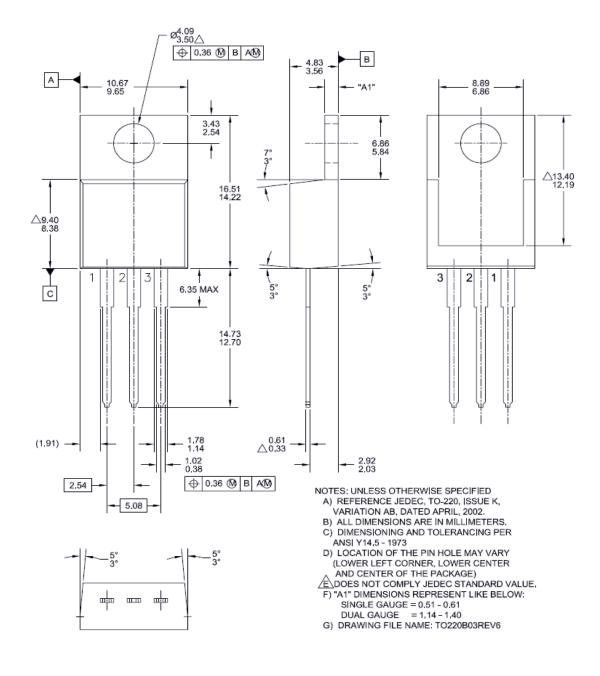


Body Diode Reverse Current



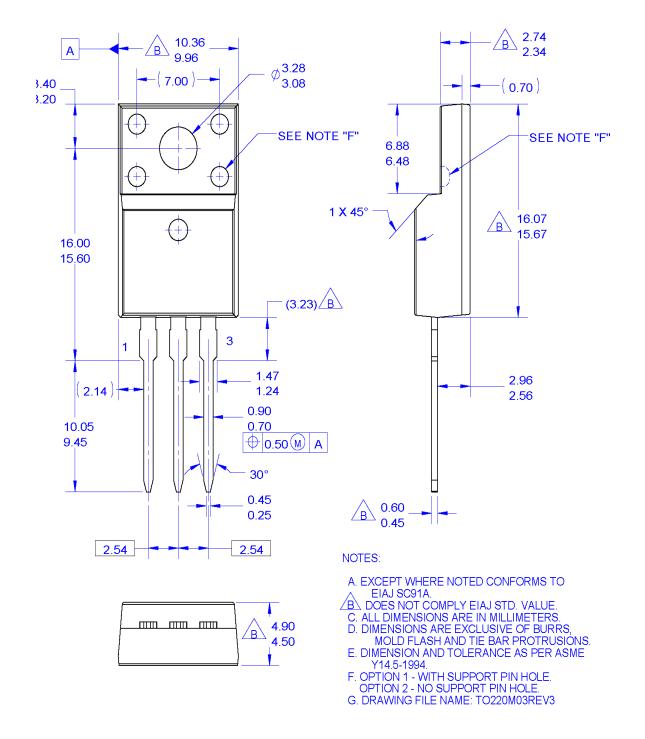
Mechanical Dimensions

TO-220B03



Package Dimensions

TO-220M03







TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

2Cool™ AccuPower™ AX-CAP[©] BitSiC™ Build it Now™ CorePLUS™ CorePOWER™ $CROSSVOLT^{\text{TM}}$

Current Transfer Logic™ DEUXPEED® Dual Cool™

EcoSPARK® EfficentMax™ ESBC™

Fairchild®

Fairchild Semiconductor® FACT Quiet Series™ FACT® $\mathsf{FAST}^{\tiny{\circledR}}$

FastvCore™ FETBench™ FPS™ F-PFS™ FRFET®

Global Power ResourceSM Green Bridge™

Green FPS™ Green FPS™ e-Series™

Gmax™ GTO™ IntelliMAX™ ISOPLANAR™

Marking Small Speakers Sound Louder and Better™

MegaBuck™ MICROCOUPLER™ MicroFET™

MicroPak™ MicroPak2™ MillerDrive™ MotionMax™ mWSaver™ OptoHiT™ OPTOLOGIC® OPTOPLANAR® (1)_® PowerTrench® PowerXS™

Programmable Active Droop™

QS™ Quiet Series™ RapidConfigure™

Saving our world, 1mW/W/kW at a time™ SignalWise™

SmartMax™ SMART START™

Solutions for Your Success™

STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™

5 GENERAL TinyBoost¹ TinyBuck™ TinyCalc™ TinyLogic[®]
TINYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TranSiC[®] TriFault Detect™ TRUECURRENT®* μSerDes™ UHC®

Ultra FRFET™ UniFET™ VCXTM VisualMax™ VoltagePlus™ XSTM

Sync-Lock™

SYSTEM ®*

*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN. WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY
FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 164